

Ultra-precision metrology – unexpected applications

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Precision metrology is the foundation of technology, and the national metrology institutes of the world excel at the most accurate and precise measurements possible. Advancing these capabilities often leads to expected improvements in advanced manufacturing, bio-medical research, next generation computing, etc. However, more often than not, these measurement advances also lead to exciting applications that no one expected or foresaw. This talk highlights some fun examples of such unexpected excursions into the unknown prompted by new measurement capabilities, such as the search for earth-like planets and the pursuit of dark matter.